



Attorney Docket No. 04216/LH

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Yoshinori IKETAKI

Serial No. : 10/821,474

Filed : April 8, 2004

For : MICROSCOPE AND ITS OPTICAL
CONTROLLING METHOD

Art Unit :

CUSTOMER NO.: 01933

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. BOX 1450
Alexandria, VA 22313-1450

Att: MS - MISSING PARTS

S I R :

Amendments to the Specification are described on page 2 of
this paper.

Remarks begin on page 3 of this paper.

CERTIFICATE OF MAILING

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Sharon Portnoy

Dated: August 12, 2004

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Please delete the abstract and add the following new
abstract:

Abstract

A microscope includes a first deflection device which
deflects first light from a first light source that excites a
molecule included in a specimen from the ground-state to a first
electronically excited state, and a two dimensionally second
5 deflecting device which deflects second light from a second light
source to excite the molecule from the first exciting state to a
second exciting state with a higher energy level. A combining
device synthesizes the deflected first light and second light on
the same optical axis or on a mutually parallel optical axis. A
10 third deflection device deflects the synthesized first light and
the second light simultaneously. Luminescence is detected by
adjusting the optical axes of the first light to the third light
by the first to third deflection device, and by overlapping part
of these lights by a beam-condensing optical system and
15 irradiating them on the specimen.